

TINCH-POUND

MIL-S-19500/403(USAF)  
AMENDMENT 1  
20 June 1990

MILITARY SPECIFICATION  
SEMICONDUCTOR DEVICE, DIODE, SILICON, SWITCHING  
TYPE 1N4500, JAN AND JANTX

This amendment forms a part of MIL-S-19500/403(USAF), dated 8 July 1968, and is approved for use by the Department of the Air Force and is available for use by all Departments and Agencies of the Department of Defense.

PAGE 1

Title: Delete and substitute as printed above.

PAGE 6

TABLE II, Subgroup 3, for Non-cavity devices only: Delete Constant acceleration test and applicable conditions.

PAGE 7

4.5.4 and 4.5.5: Delete in their entirety.

PAGE 8

4.5.5.1 and 4.5.5.2: Delete in their entirety.

4.5.6, delete and substitute as follows:

"4.5.6 Hermetic seal (gross leak) test. All devices will be gross leak tested in accordance with MIL-STD-750, method 1071, condition D or E. If condition E is chosen for nontransparent devices, after alcohol rinse, the devices shall be dried and placed on a clean, white blotter and observed for any evidence of dye."

4.5.6.1, 4.5.6.2, and 4.5.6.3: Delete in their entirety.

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FIGURE 2: Delete in its entirety.

CONCLUDING MATERIAL

Custodian:  
Air Force - 17

Review activities:  
Air Force - 11, 85

Preparing activity:  
Air Force - 17

Agent:  
DLA - ES

(Project 5961-F003)